L Number	Hits	Search Text	DB	Time stamp
1	3783	(generat$3 or creat$3 or build$3) near3 test$3 same (IC or integrated near circuit)	USPAT; EPO; JPO; DERWENT; IBM_TDB	2003/11/07 11:39
2	1205	((generat$3 or creat$3 or build$3) near3 test$3 same (IC or integrated near circuit)) and (determin$3 or find$3 or check$3 or verify$4) near4 test$3 and data	USPAT; EPO; JPO; DERWENT; IBM_TDB	2003/11/07 13:49
3	367	(((generat$3 or creat$3 or build$3) near3 test$3 same (IC or integrated near circuit)) and (determin$3 or find$3 or check$3 or verify$4) near4 test$3 and data) and (first and second) near2 test$3	USPAT; EPO; JPO; DERWENT; IBM_TDB	2003/11/07 12:45
4	2	((((generat$3 or creat$3 or build$3) near3 test$3 same (IC or integrated near circuit)) and (determin$3 or find$3 or check$3 or verify$4) near4 test$3 and data) and (first and second) near2 test$3) and (syntax near tree or AST)	USPAT; EPO; JPO; DERWENT; IBM_TDB	2003/11/07 12:02
5	18	((((generat$3 or creat$3 or build$3) near3 test$3 same (IC or integrated near circuit)) and (determin$3 or find$3 or check$3 or verify$4) near4 test$3 and data) and (first and second) near2 test$3) and tree	USPAT; EPO; JPO; DERWENT; IBM_TDB	2003/11/07 12:02
6	68	(((generat$3 or creat$3 or build$3) near3 test$3 same (IC or integrated near circuit)) and (determin$3 or find$3 or check$3 or verify$4) near4 test$3 and data) and (first and second) same test$3 same success$5	USPAT; EPO; JPO; DERWENT; IBM_TDB	2003/11/07 12:48
7	5	(((generat$3 or creat$3 or build$3) near3 test$3 same (IC or integrated near circuit)) and (determin$3 or find$3 or check$3 or verify$4) near4 test$3 and data) and (first and second) same test$3 same success$5 and tree	USPAT; EPO; JPO; DERWENT; IBM_TDB	2003/11/07 12:48
8	153	((generat$3 or creat$3 or build$3) near3 test$3 same (IC or integrated near circuit)) and (determin$3 or find$3 or check$3 or verify$4) near4 first same test$3 and second near4 test	USPAT; EPO; JPO; DERWENT; IBM_TDB	2003/11/07 13:50
9	0	(((generat$3 or creat$3 or build$3) near3 test$3 same (IC or integrated near circuit)) and (determin$3 or find$3 or check$3 or verify$4) near4 first same test$3 and second near4 test) and (abstract near syntax near tree or syntax near tree)	USPAT; EPO; JPO; DERWENT; IBM_TDB	2003/11/07 13:54
10	5	(((generat$3 or creat$3 or build$3) near3 test$3 same (IC or integrated near circuit)) and (determin$3 or find$3 or check$3 or verify$4) near4 first same test$3 and second near4 test) and tree	USPAT; EPO; JPO; DERWENT; IBM_TDB	2003/11/07 13:54
-	26	(717/$.ccls. or 712/$.ccls. or 714/$.ccls.) and (insert$3 or instrument$6) same prefetch and (feedback or interact$6)	USPAT; EPO; JPO; DERWENT; IBM_TDB	2003/11/07 11:37
-	26	(717/$.ccls. or 714/$.ccls.) and (abstract near syntax near tree or syntax near tree) and (generat$3 or build$3 or design$3 or develop$3 or creat$3) near3 test$3	USPAT; EPO; JPO; DERWENT; IBM_TDB	2002/10/23 14:12
-	15	(717/$.ccls. or 714/$.ccls.) and (abstract near syntax near tree or syntax near tree) and (generat$3 or build$3 or design$3 or develop$3 or creat$3) near3 test$3 and translat$3 same execut$3	USPAT; EPO; JPO; DERWENT; IBM_TDB	2002/10/23 13:14

-		5	(717/\$.ccls. or 714/\$.ccls.) and (abstract near syntax near tree or syntax near tree) and (generat\$3 or build\$3 or design\$3 or develop\$3 or creat\$3) near3 test\$3 and (abstract near syntax near tree or AST) same (mutat\$3 or chang\$3 or reorganiz\$3)	USPAT; EPO; JPO; DERWENT; IBM_TDB	2002/10/23 14:44